

**Search Notes**

Application/Control No.

10/820,144

Examiner

Shin-Lin Chen

Applicant(s)/Patent under  
Reexamination

CHANG ET AL.

Art Unit

1632

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Updated.	12/12/2007	<i>SLC</i>